



PD-91549B

HEXFET® POWER MOSFET

IRFN250
JANTX2N7225U
JANTXV2N7225U
[REF:MIL-PRF-19500/592]
N - CHANNEL

200 Volt, 0.100Ω MOSFET

HEXFET® power MOSFET technology is the key to InternationalRectifier's advanced line of power MOSFET transistors. The efficient geometry achieves very low on-state resistance combined with high transconductance.

HEXFET® power MOSFET transistors also feature all of the well-established advantages of MOSFETs, such as voltage control, very fast switching, ease of paralleling and electrical parameter temperature stability. They are well-suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers and high-energy pulse circuits.

The Surface Mount Device (SMD-1) package represents another step in the continual evolution of surface mount technology. The SMD-1 will give designers the extra flexibility they need to increase circuit board density. International Rectifier has engineered the SMD-1 package to meet the specific needs of the power market by increasing the size of the bottom source pads, thereby enhancing the thermal and electrical performance.

Absolute Maximum Ratings

	Parameter		Units
ID @ VGS = 10V, TC = 25°C	Continuous Drain Current	27.4	A
ID @ VGS = 10V, TC = 100°C	Continuous Drain Current	17	
IDM	Pulsed Drain Current ①	110	
PD @ TC = 25°C	Max. Power Dissipation	150	W
	Linear Derating Factor	1.2	W/C
VGS	Gate-to-Source Voltage	±20	V
EAS	Single Pulse Avalanche Energy ②	500	mJ
IAR	Avalanche Current ①	27.4	A
EAR	Repetitive Avalanche Energy ①	15.0	mJ
dv/dt	Peak Diode Recovery dv/dt ③	5.0	V/ns
TJ	Operating Junction	-55 to 150	°C
TSTG	Storage Temperature Range		
	Package Mounting Surface Temperature	300 (for 5 seconds)	
	Weight	2.6 (typical)	g

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Electrical Characteristics @ $T_j = 25^\circ\text{C}$ (Unless Otherwise Specified)

	Parameter	Min	Typ	Max	Units	Test Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	200	—	—	V	$\text{V}_{\text{GS}} = 0\text{V}, \text{I}_D = 1.0\text{mA}$
$\Delta \text{BV}_{\text{DSS}}/\Delta T_j$	Temperature Coefficient of Breakdown Voltage	—	0.29	—	$\text{V}/^\circ\text{C}$	Reference to 25°C , $\text{I}_D = 1.0\text{mA}$
$\text{R}_{\text{DS(on)}}$	Static Drain-to-Source On-State Resistance	—	—	0.100	Ω	$\text{V}_{\text{GS}} = 10\text{V}, \text{I}_D = 17\text{A}$ ④
		—	—	0.105		$\text{V}_{\text{GS}} = 10\text{V}, \text{I}_D = 27.4\text{A}$
$\text{V}_{\text{GS(th)}}$	Gate Threshold Voltage	2.0	—	4.0	V	$\text{V}_{\text{DS}} = \text{V}_{\text{GS}}, \text{I}_D = 250\mu\text{A}$
g_{fs}	Forward Transconductance	9.0	—	—	$\text{S} (\text{V})$	$\text{V}_{\text{DS}} > 15\text{V}, \text{I}_{\text{DS}} = 17\text{A}$ ④
I_{DSS}	Zero Gate Voltage Drain Current	—	—	25	μA	$\text{V}_{\text{DS}} = 0.8 \times \text{Max Rating}, \text{V}_{\text{GS}} = 0\text{V}$
		—	—	250		$\text{V}_{\text{DS}} = 0.8 \times \text{Max Rating}$ $\text{V}_{\text{GS}} = 0\text{V}, \text{T}_j = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Leakage Forward	—	—	100	nA	$\text{V}_{\text{GS}} = 20\text{V}$
I_{GSS}	Gate-to-Source Leakage Reverse	—	—	-100		$\text{V}_{\text{GS}} = -20\text{V}$
Q_g	Total Gate Charge	—	—	115	nC	$\text{V}_{\text{GS}} = 10\text{V}, \text{I}_D = 27.4\text{A}$
Q_{gs}	Gate-to-Source Charge	—	—	22		$\text{V}_{\text{DS}} = \text{Max Rating} \times 0.5$
Q_{gd}	Gate-to-Drain ('Miller') Charge	—	—	60		
$t_{\text{d(on)}}$	Turn-On Delay Time	—	—	35	ns	$\text{V}_{\text{DD}} = 50\text{V}, \text{I}_D = 27.4\text{A}, \text{R}_G = 2.35\Omega, \text{V}_{\text{GS}} = 10\text{V}$
t_r	Rise Time	—	—	190		
$t_{\text{d(off)}}$	Turn-Off Delay Time	—	—	170		
t_f	Fall Time	—	—	130		
$\text{L}_{\text{S+LD}}$	Total Inductance	—	4.0	—	nH	Measured from the center of drain pad to center of source pad
C_{iss}	Input Capacitance	—	3500	—	pF	$\text{V}_{\text{GS}} = 0\text{V}, \text{V}_{\text{DS}} = 25\text{V}$ $f = 1.0\text{MHz}$
C_{oss}	Output Capacitance	—	700	—		
C_{rss}	Reverse Transfer Capacitance	—	110	—		

Source-Drain Diode Ratings and Characteristics

	Parameter	Min	Typ	Max	Units	Test Conditions
I_{S}	Continuous Source Current (Body Diode)	—	—	27.4	A	
I_{SM}	Pulse Source Current (Body Diode) ①	—	—	110		
V_{SD}	Diode Forward Voltage	—	—	1.9	V	$\text{T}_j = 25^\circ\text{C}, \text{I}_{\text{S}} = 27.4\text{A}, \text{V}_{\text{GS}} = 0\text{V}$ ④
t_{rr}	Reverse Recovery Time	—	—	950	ns	$\text{T}_j = 25^\circ\text{C}, \text{I}_{\text{F}} = 27.4\text{A}, \text{dI/dt} \geq 100\text{A}/\mu\text{s}$
Q_{RR}	Reverse Recovery Charge	—	—	9.0	μC	$\text{V}_{\text{DD}} \leq 30\text{V}$ ④
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by $\text{L}_{\text{S+LD}}$.				

Thermal Resistance

	Parameter	Min	Typ	Max	Units	Test Conditions
R_{thJC}	Junction-to-Case	—	—	0.83	$^\circ\text{C/W}$	
$\text{R}_{\text{thJ-PCB}}$	Junction-to-PC board	—	3.0	—		Soldered to a copper-clad PC board

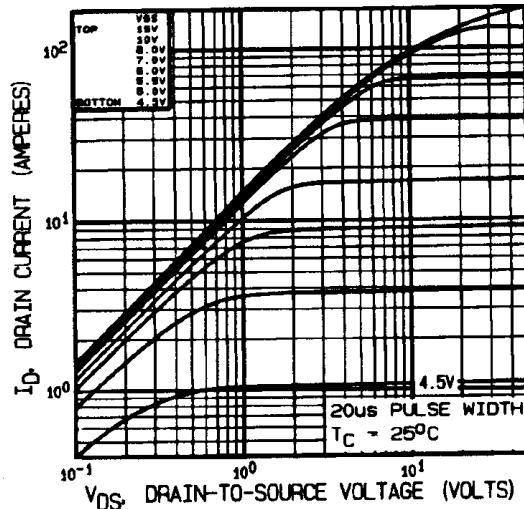


Fig 1. Typical Output Characteristics

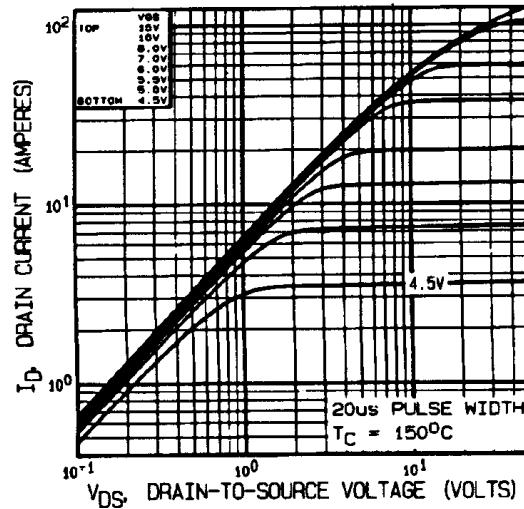


Fig 2. Typical Output Characteristics

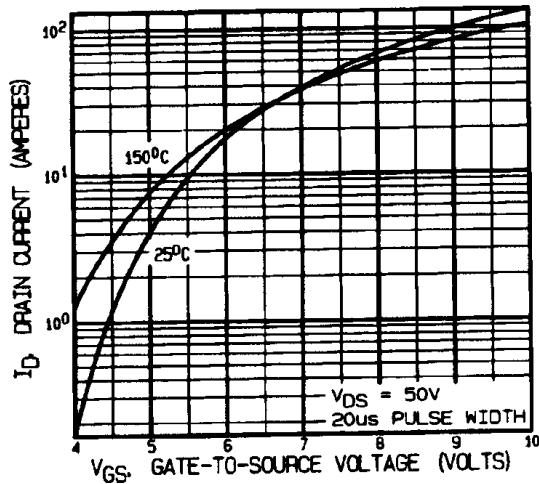


Fig 3. Typical Transfer Characteristics

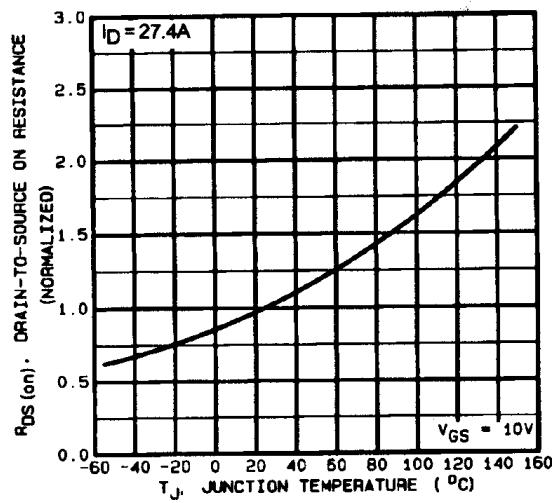


Fig 4. Normalized On-Resistance
Vs. Temperature

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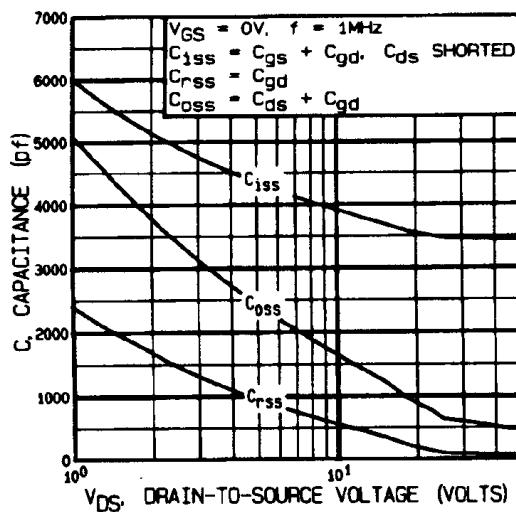


Fig 5. Typical Capacitance Vs.
Drain-to-Source Voltage

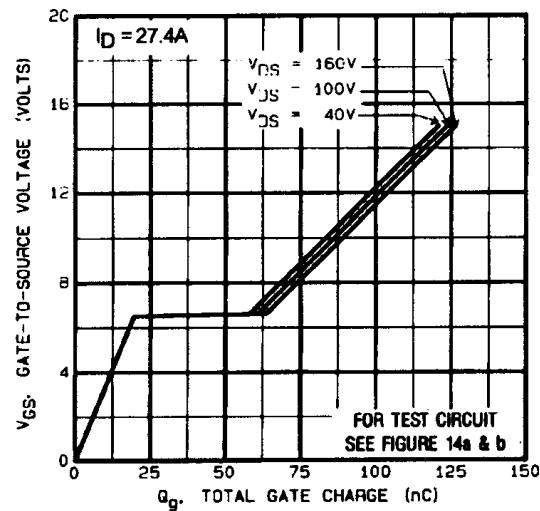


Fig 6. Typical Gate Charge Vs.
Gate-to-Source Voltage

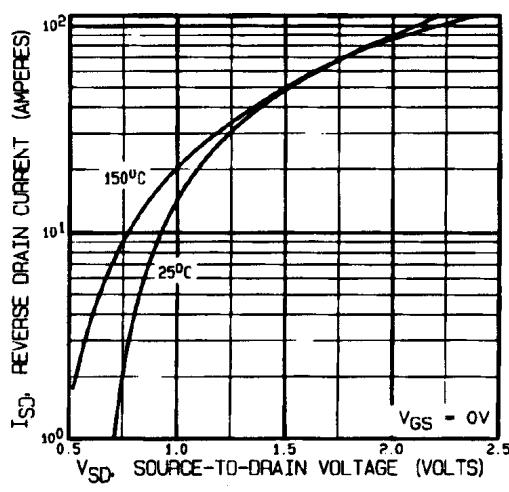


Fig 7. Typical Source-Drain Diode
Forward Voltage

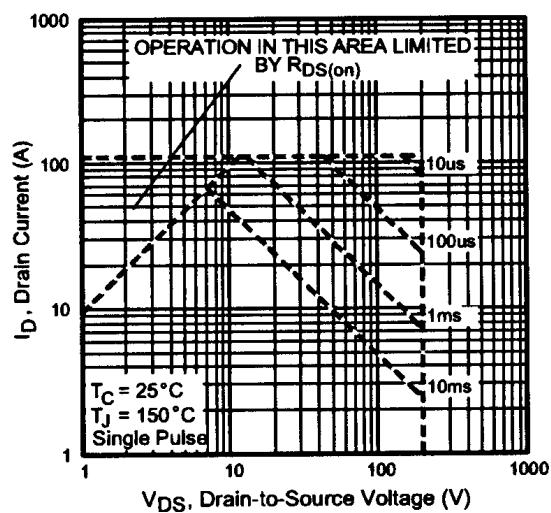


Fig 8. Maximum Safe Operating Area

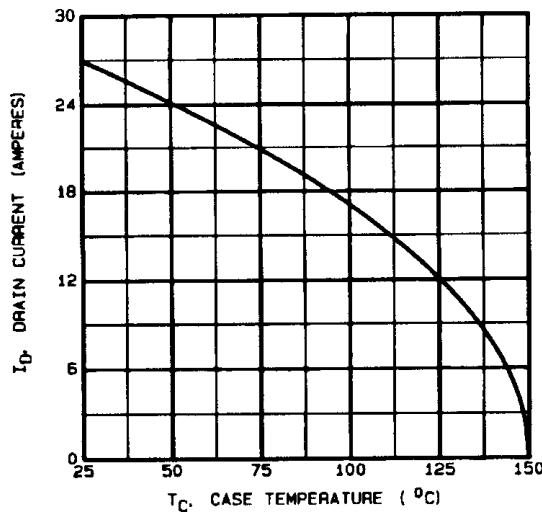


Fig 9. Maximum Drain Current Vs.
Case Temperature

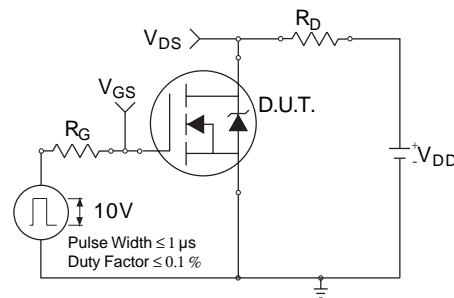


Fig 10a. Switching Time Test Circuit

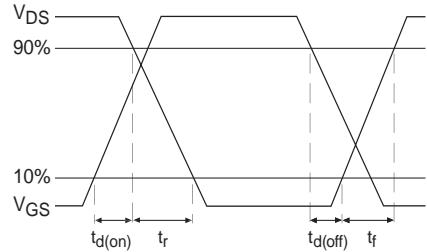


Fig 10b. Switching Time Waveforms

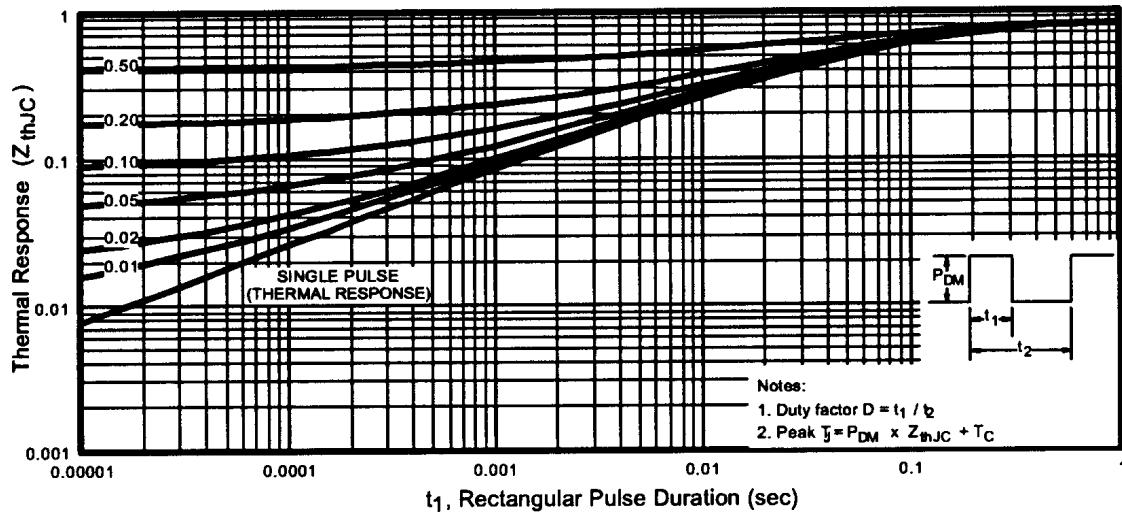


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

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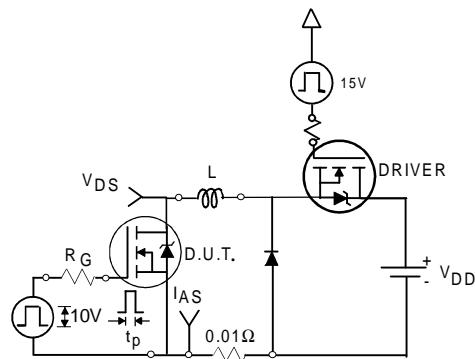


Fig 12a. Unclamped Inductive Test Circuit

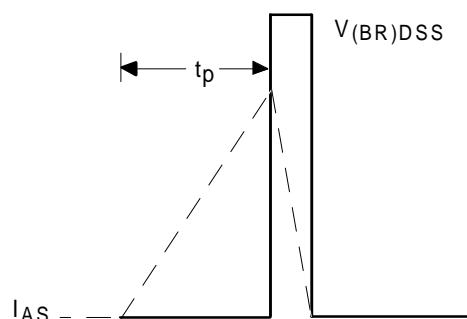


Fig 12b. Unclamped Inductive Waveforms

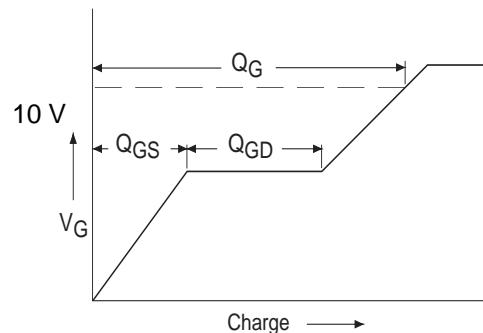


Fig 13a. Basic Gate Charge Waveform

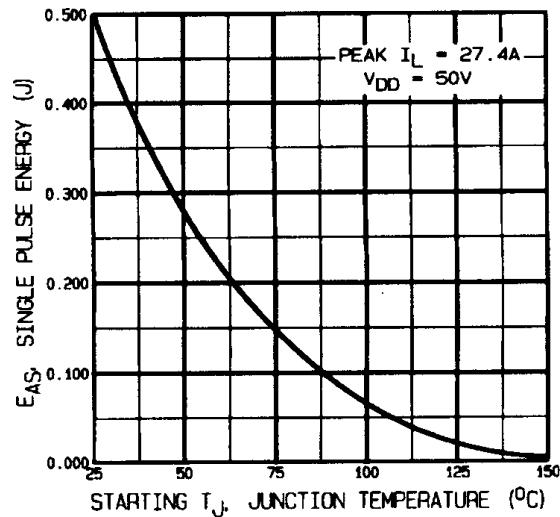


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

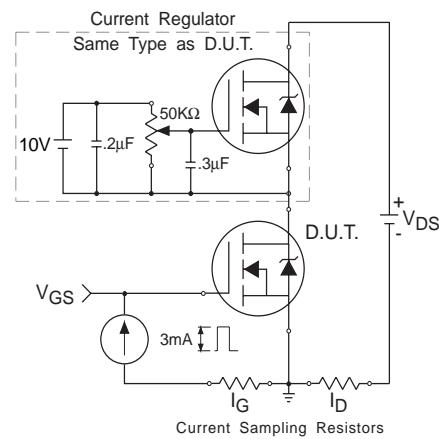


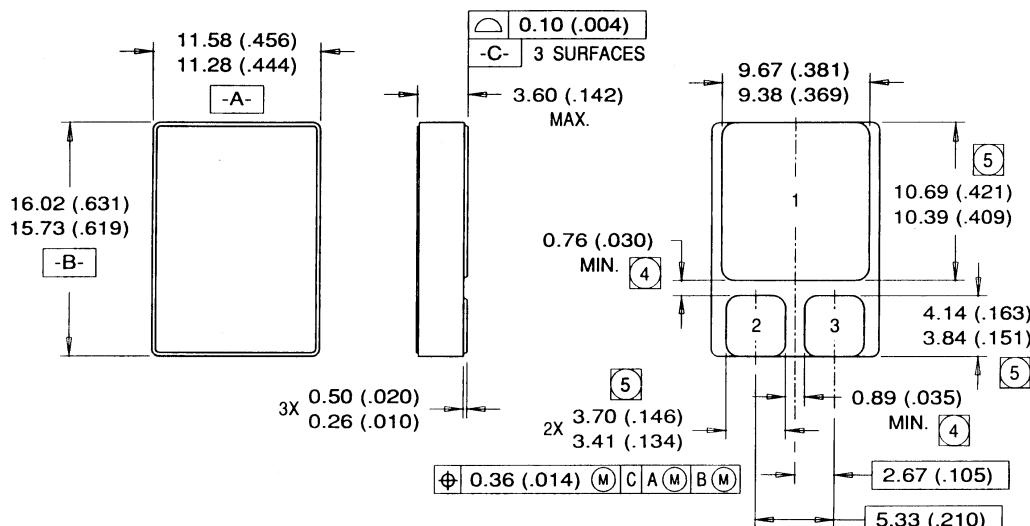
Fig 13b. Gate Charge Test Circuit

Notes:

- ① Repetitive Rating; Pulse width limited by maximum junction temperature.
- ② V_{DD} = 25 V, Starting T_J = 25°C,
Peak I_L = 27.4 A, V_{GS} = 10 V, 25 ≤ R_G ≤ 200Ω

- ③ I_{SD} ≤ 27.4 A, dI/dt ≤ 190 A/μs,
V_{DD} ≤ 200 V, T_J ≤ 150°C
- ④ Pulse width ≤ 300 μs; Duty Cycle ≤ 2%

Case Outline and Dimensions — SMD-1



NOTES:

1. DIMENSIONING & TOLERANCING PER ANSI Y14.5M-1982
2. CONTROLLING DIMENSION: INCH.
3. DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
4. DIMENSION INCLUDES METALLIZATION FLASH.
5. DIMENSION DOES NOT INCLUDE METALLIZATION FLASH.

PAD ASSIGNMENTS

- | | |
|---|----------|
| 1 | = DRAIN |
| 2 | = GATE |
| 3 | = SOURCE |

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Data and specifications subject to change without notice. 12/99